

A METHOD OF MEASURING SMALL PADS ON A SUBSTRATE

Milad F. Tabet

ABSTRACT

5 A method of measuring a small area on a substrate with an ellipsometer,
comprising orienting a substrate with respect to the ellipsometer such that an elliptical
light spot produced by the ellipsometer fits diagonally within the test area. Then
measuring the surface properties of the substrate within the test area with the
ellipsometer.

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